

Synthesis of the Defect-Controlled Few-Layer WSe₂ via Pulsed Laser Deposition

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Abstract

WSe₂, one of the transition metal dichalcogenide (TMD) materials, has been intensively interested owing to its fascinating properties, such as layer-dependent bandgap (~1.7 eV for monolayer and ~1.2 eV for bulk). Harnessing of layer-dependence could enable to tune not only the bandgap but also electrical and optical properties, making TMDs attractive. Therefore, properly controlling the number of layers of TMDs is beneficial for the design and optimization of novel devices.

Recently, many studies on the synthesis methods of TMD thin films have been reported. Among them, pulsed

Raman spectrum analysis



laser deposition (PLD) could achieve low growth temperature and short deposition time. The limited source transfer by PLD is advantageous for precise control of the number of layers. It is also easy for the fabrication of heterojunction with other materials through in situ deposition without the additional transfer process. However, it remains major challenges to synthesize high-quality stoichiometric thin films composed of micron-sized grains by PLD.

Our group successfully fabricated the WSe₂ thin films at low temperature via In situ chalcogen-evaporated PLD system. Using our PLD system, selenium vacancies in WSe₂ were compensated by flow control of selenium gas. Further, we obtained increased crystallinity of WSe₂ films by reducing the concentration of water and suppressing the unnecessary nucleation via the NaCl-assisted deposition process. By carrying out Raman spectral analysis and electrical measurements, we have confirmed our WSe₂ thin films show improved properties compared to those deposited in conventional PLD methods. We expect that our study will pave the way for the development of efficient TMDs synthesis method and be applied for the fabrication of next-generation electronic devices through follow-up studies.

X-ray Photoelectron Spectroscopy (XPS)

Substitutional Oxygen can enhance the conductivity and photoconductivity of TMDs materials.

Experiments

- In situ Chalcogen-Evaporated Pulsed Laser Deposition (PLD)
- Challenges of injection of the pure chalcogen flux into UHV chamber
 - -> Due to the solid state of chalcogen elements at room temperature,
 - a gas line blockage occurred when the chalcogen gas evaporate from the source.
- ***** To overcome this issue, we specially designed the in situ chalcogen-evaporated PLD system.

Selenium flux control by evaporation temperature

Setting Temp. vs. Se flux
 exposed SiO₂/Si subs. for 20 min
 ramping time: 90 min (for heating)
 Se melting point: 220.1°C at 760 Torr

- 400°C : 1300 ~ 1000 nm/min 350° C : 48.5 ~ 23.0 um/min 300° C : 8.5 ~ 4.0 nm/min (In this work) + WSe₂ growth rate: 0.252 nm/min
- Time (min)
- By directly controlling the temperature of canister containing selenium, but it is slightly different from the actual selenium temperature.
 Selenium flux was estimated through the selenium growth rate
 - as a function of temperature.
 - * The phases of WSe_2 on SiO_2/Si and NaCl(001) were confirmed.

Conclusion

2.26

19.12%

SEED

1. We synthesized WSe₂ films on SiO₂/Si and NaCl(001) substrates

Without Se flux

NaCI(001)

- via in situ chalcogen-evaporated PLD which can compensate the selenium in WSe₂ layer.
- 2. More uniform WSe₂ films were obtained with additional Se flux on SiO₂/Si, while the effect of Se flux on WSe₂ films on NaCl(001) is not dominant at this stage.
- 3. Measuring the electrical and optical properties to evaluate the precise effect of Se flux on WSe₂ thin films is ongoing.

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